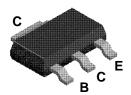
Index of /ds/FZ/

	Name	Last modified	Size	Description
₩_	Parent Directory			
	FZT560.pdf	03-Dec-99 15:45	44K	
	FZT560A.pdf	03-Dec-99 15:45	44K	
<u> </u>	FZT649.pdf	22-Dec-99 00:08	28K	
	FZT660.pdf	03-Dec-99 15:45	44K	
<u> </u>	FZT660A.pdf	03-Dec-99 15:45	44K	
	FZT749.pdf	22-Dec-99 00:08	27K	
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FZT560 / FZT560A



SOT-223

NPN Low Saturation Transistor

These devices are designed with high current gain and low saturation voltage with collector currents up to 3A continuous.

Absolute Maximum Ratings* T_{A = 25°C unless otherwise noted}

Symbol	Parameter	FZT560/FZT560A	Units
V _{CEO}	Collector-Emitter Voltage	60	V
V _{CBO}	Collector-Base Voltage	80	V
V _{EBO}	Emitter-Base Voltage	5	V
Ic	Collector Current - Continuous	3	Α
T _J , T _{stg}	Operating and Storage Junction Temperature Range	-55 to +150	°C

^{*}These ratings are limiting values above which the serviceability of any semiconductor device may be impaired.

NOTES:

- 1) These ratings are based on a maximum junction temperature of 150°C.
- 2) These are steady state limits. The factory should be consulted on applications involving pulsed or low duty cycle operations.

Thermal Characteristics T_{A = 25°C unless otherwise noted}

Symbol	Characteristic	Max	Units
		FZT560/FZT560A	
P _D	Total Device Dissipation	2	W
$R_{\theta JA}$	Thermal Resistance, Junction to Ambient	62.5	°C/W

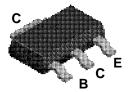
NPN Lo	w Saturation Transistor				
Electric	al Characteristics T _{A = 25°C unless of}	otherwise noted			
Symbol	Parameter	Test Conditions	Min	Max	Units
OFF CHA	RACTERISTICS				
BV _{CEO}	Collector-Emitter Breakdown Voltage	I _C = 10 mA	60		V
BV _{CBO}	Collector-Base Breakdown Voltage	I _C = 100 μA	80		V
BV _{EBO}	Emitter-Base Breakdown Voltage	I _E = 100 μA	5		V
I _{CBO}	Collector Cutoff Current	V _{CB} = 30 V		100	nA
		V _{CB} = 30 V, T _A =100°C		10	uA
I _{EBO}	Emitter Cutoff Current	V _{EB} = 4V		100	nA
ON CHAE	RACTERISTICS*			I	<u>.I</u>
h _{FE}	DC Current Gain	I _C = 100 mA, V _{CE} = 2 V	70		_
''FE		$I_C = 500 \text{ mA}, V_{CE} = 2 \text{ V}$ FZT560	100	300	
		FZT560A	250	550	
		$I_C = 1 A$, $V_{CE} = 2 V$	80		
		$I_C = 3 A, V_{CE} = 2 V$	25		
V _{CE(sat)}	Collector-Emitter Saturation Voltage	I _C = 1 A, I _B = 100 mA		300	mV
, ,		I _C = 3 A, I _B = 300 mA FZT560		450	
		FZT560A		400	
$V_{BE(sat)}$	Base-Emitter Saturation Voltage	I _C = 1 A, I _B = 100 mA		1.25	V
V _{BE(on)}	Base-Emitter On Voltage	I _C = 1 A, V _{CE} = 2 V		1	V
SMALL S	IGNAL CHARACTERISTICS				
C _{obo}	Output Capacitance	V _{CB} = 10 V, I _E = 0, f = 1MHz		30	pF
f _T	Transition Frequency	I _C = 100 mA,V _{CE} = 5 V, f=100MHz	75		-
	•	•	•	•	

*Pulse Test: Pulse Width \leq 300 μ s, Duty Cycle \leq 2.0%



July 1998

FZT649



SOT-223

NPN Low Saturation Transistor

These devices are designed with high current gain and low saturation voltage with collector currents up to 3A continuous.

Absolute Maximum Ratings* T_{A = 25°C unless otherwise noted}

Symbol	Parameter	FZT649	Units
V _{CEO}	Collector-Emitter Voltage	25	V
V _{CBO}	Collector-Base Voltage	35	V
V _{EBO}	Emitter-Base Voltage	5	V
Ic	Collector Current - Continuous	3	А
T _J , T _{stg}	Operating and Storage Junction Temperature Range	-55 to +150	°C

^{*}These ratings are limiting values above which the serviceability of any semiconductor device may be impaired.

NOTES:

- 1) These ratings are based on a maximum junction temperature of 150°C.
- 2) These are steady state limits. The factory should be consulted on applications involving pulsed or low duty cycle operations.

Thermal Characteristics $T_{A=25^{\circ}\text{C unless otherwise noted}}$

Symbol	Characteristic	Max	Units
		FZT649	
P _D	Total Device Dissipation	2	W
R _{θJA}	Thermal Resistance, Junction to Ambient	62.5	°C/W

NPN Low Saturation Transistor

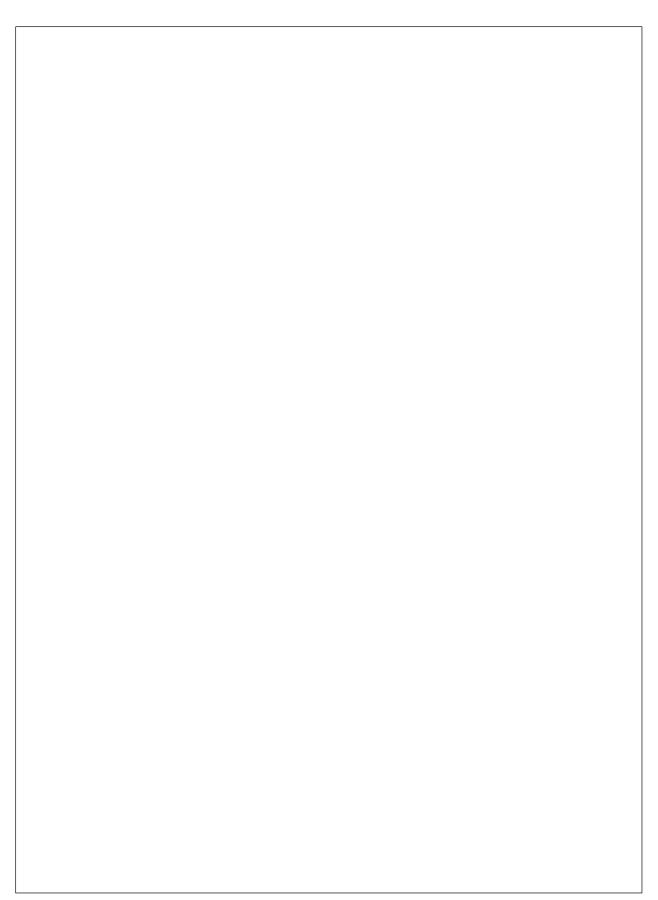
(continued)

Electrical Characteristics

 $T_{\text{A}\,=\,25^{\circ}\text{C}\,\text{unless otherwise noted}}$

Symbol	Parameter	Test Conditions	Min	Max	Units
OFF CHA	RACTERISTICS				
BV _{CEO}	Collector-Emitter Breakdown Voltage	I _C = 10 mA	25		V
BV _{CBO}	Collector-Base Breakdown Voltage	I _C = 100 μA	35		V
BV _{EBO}	Emitter-Base Breakdown Voltage	I _E = 100 μA	5		V
I _{CBO}	Collector Cutoff Current	V _{CB} = 30 V		100	nA
		$V_{CB} = 30 \text{ V}, T_A = 100^{\circ}\text{C}$		10	uA
I _{EBO}	Emitter Cutoff Current	V _{EB} = 4V		100	nA
ON CHAF	RACTERISTICS*				
h _{FE}	DC Current Gain	$I_C = 50 \text{ mA}, V_{CE} = 2 \text{ V}$	70		-
		I _C = 1 A, V _{CE} = 2 V	100	300	
		$I_C = 2 A$, $V_{CE} = 2 V$	75		
		I _C = 6 A, V _{CE} = 2 V	15		
V _{CE(sat)}	Collector-Emitter Saturation Voltage	I _C = 1 A, I _B = 100 mA		300	mV
()		I _C = 3 A, I _B = 300 mA		600	
V _{BE(sat)}	Base-Emitter Saturation Voltage	I _C = 1 A, I _B = 100 mA		1.25	V
V _{BE(on)}	Base-Emitter On Voltage	I _C = 1 A, V _{CE} = 2 V		1	V
SMALL S	IGNAL CHARACTERISTICS				
C _{obo}	Output Capacitance	V _{CB} = 10 V, I _E = 0, f = 1MHz		50	pF
f _T	Transition Frequency	I _C = 100 mA,V _{CE} = 5 V, f=100MHz	150		-

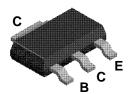
*Pulse Test: Pulse Width $\leq 300~\mu s,~Duty~Cycle \leq 2.0\%$





July 1998

FZT660 / FZT660A



SOT-223

PNP Low Saturation Transistor

These devices are designed with high current gain and low saturation voltage with collector currents up to 3A continuous.

Absolute Maximum Ratings* T_{A = 25°C unless otherwise noted}

Symbol	Parameter	FZT660/FZT660A	Units
V _{CEO}	Collector-Emitter Voltage	60	V
V _{CBO}	Collector-Base Voltage	80	V
V _{EBO}	Emitter-Base Voltage	5	V
Ic	Collector Current - Continuous	3	А
T _J , T _{stg}	Operating and Storage Junction Temperature Range	-55 to +150	°C

^{*}These ratings are limiting values above which the serviceability of any semiconductor device may be impaired.

NOTES:

- 1) These ratings are based on a maximum junction temperature of 150°C.
- 2) These are steady state limits. The factory should be consulted on applications involving pulsed or low duty cycle operations.

Thermal Characteristics T_{A = 25°C unless otherwise noted}

Symbol	Characteristic	Max	Units
		FZT660/FZT660A	
P _D	Total Device Dissipation	2	W
$R_{\theta JA}$	Thermal Resistance, Junction to Ambient	62.5	°C/W

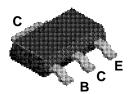
PNP Lov (continued)	w Saturation Transistor				
Electrica	al Characteristics T _{A = 25°C unless of}	otherwise noted			
Symbol	Parameter	Test Conditions	Min	Max	Units
OFF CHAI	RACTERISTICS			I	.1
BV _{CEO}	Collector-Emitter Breakdown Voltage	I _C = 10 mA	60		V
BV _{CBO}	Collector-Base Breakdown Voltage	I _C = 100 μA	80		V
BV _{EBO}	Emitter-Base Breakdown Voltage	ΙΕ = 100 μΑ	5		V
Ісво	Collector Cutoff Current	V _{CB} = 30 V		100	nA
		V _{CB} = 30 V, T _A =100°C		10	uA
I _{EBO}	Emitter Cutoff Current	V _{EB} = 4V		100	nA
ON CHAR	ACTERISTICS*			l	
h _{FE}	DC Current Gain	I _C = 100 mA, V _{CE} = 2 V	70		-
		$I_C = 500 \text{ mA}, V_{CE} = 2 \text{ V } \text{ FZT660}$	100	300	
		FZT660A I _C = 1 A, V _{CE} = 2 V	250	550	
		$I_{C} = 1 \text{ A}, V_{CE} = 2 \text{ V}$ $I_{C} = 3 \text{ A}, V_{CE} = 2 \text{ V}$	80 25		
Vosc	Collector-Emitter Saturation Voltage	I _C = 1 A, I _B = 100 mA	25	300	mV
V _{CE(sat)}		$I_C = 3 \text{ A}, I_B = 300 \text{ mA}$ FZT660		550	
		FZT660A		500	
V _{BE(sat)}	Base-Emitter Saturation Voltage	I _C = 1 A, I _B = 100 mA		1.25	V
V _{BE(on)}	Base-Emitter On Voltage	I _C = 1 A, V _{CE} = 2 V		1	V
SMALL SI	GNAL CHARACTERISTICS				
C _{obo}	Output Capacitance	V _{CB} = 10 V, I _E = 0, f = 1MHz		45	pF
f _T	Transition Frequency	I _C = 100 mA,V _{CE} = 5 V, f=100MHz	75		-
	1				

*Pulse Test: Pulse Width $\leq 300~\mu s$, Duty Cycle $\leq 2.0\%$



July 1998

FZT749



SOT-223

PNP Low Saturation Transistor

These devices are designed with high current gain and low saturation voltage with collector currents up to 3A continuous.

Absolute Maximum Ratings* $T_{A=25^{\circ}C \text{ unless otherwise noted}}$

Symbol	Parameter	FZT749	Units
V _{CEO}	Collector-Emitter Voltage	25	V
V _{CBO}	Collector-Base Voltage	35	V
V _{EBO}	Emitter-Base Voltage	5	V
Ic	Collector Current - Continuous	3	А
T _{J,} T _{stg}	Operating and Storage Junction Temperature Range	-55 to +150	°C

 $^{^{\}star}$ These ratings are limiting values above which the serviceability of any semiconductor device may be impaired.

NOTES:

- 1) These ratings are based on a maximum junction temperature of 150°C.
- 2) These are steady state limits. The factory should be consulted on applications involving pulsed or low duty cycle operations.

Thermal Characteristics T_{A = 25°C unless otherwise noted}

Symbol	Characteristic	Max	Units
		FZT749	
P _D	Total Device Dissipation	2	W
$R_{\theta JA}$	Thermal Resistance, Junction to Ambient	62.5	°C/W

PNP Low Saturation Transistor

(continued)

Electrical Characteristics

 $T_{\text{A}\,=\,25^{\circ}\text{C}\,\text{unless otherwise noted}}$

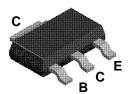
Symbol	Parameter	Test Conditions	Min	Max	Units
OFF CHA	RACTERISTICS				
BV _{CEO}	Collector-Emitter Breakdown Voltage	I _C = 10 mA	25		V
BV _{CBO}	Collector-Base Breakdown Voltage	I _C = 100 μA	35		V
BV _{EBO}	Emitter-Base Breakdown Voltage	I _E = 100 μA	5		V
I _{CBO}	Collector Cutoff Current	V _{CB} = 30 V		100	nA
		$V_{CB} = 30 \text{ V}, T_A = 100^{\circ}\text{C}$		10	uA
I _{EBO}	Emitter Cutoff Current	V _{EB} = 4V		100	nA
ON CHAF	ACTERISTICS*				
h _{FE}	DC Current Gain	I _C = 50 mA, V _{CE} = 2 V	70		-
		I _C = 1 A, V _{CE} = 2 V	100	300	
		I _C = 2 A, V _{CE} = 2 V	75		
		I _C = 6 A, V _{CE} = 2 V	15		
V _{CE(sat)}	Collector-Emitter Saturation Voltage	I _C = 1 A, I _B = 100 mA		300	mV
		I _C = 3 A, I _B = 300 mA		600	
V _{BE(sat)}	Base-Emitter Saturation Voltage	I _C = 1 A, I _B = 100 mA		1.25	V
V _{BE(on)}	Base-Emitter On Voltage	I _C = 1 A, V _{CE} = 2 V		1	V
SMALL S	IGNAL CHARACTERISTICS				
C _{obo}	Output Capacitance	V _{CB} = 10 V, I _E = 0, f = 1MHz		100	pF
f _T	Transition Frequency	I _C = 100 mA,V _{CE} = 5 V, f=100MHz	100		-

*Pulse Test: Pulse Width $\leq 300~\mu s,~Duty~Cycle \leq 2.0\%$



July 1998

FZT790A



SOT-223

PNP Low Saturation Transistor

These devices are designed with high current gain and low saturation voltage with collector currents up to 3A continuous.

Absolute Maximum Ratings* T_{A = 25°C unless otherwise noted}

Symbol	Parameter	FZT790A	Units
V _{CEO}	Collector-Emitter Voltage	40	V
V _{CBO}	Collector-Base Voltage	50	V
V _{EBO}	Emitter-Base Voltage	5	V
Ic	Collector Current - Continuous	3	А
T _J , T _{stg}	Operating and Storage Junction Temperature Range	-55 to +150	°C

^{*}These ratings are limiting values above which the serviceability of any semiconductor device may be impaired.

NOTES:

- 1) These ratings are based on a maximum junction temperature of 150°C.
- 2) These are steady state limits. The factory should be consulted on applications involving pulsed or low duty cycle operations.

Thermal Characteristics $T_{A = 25^{\circ}C \text{ unless otherwise noted}}$

Symbol	Characteristic	Max	Units
		FZT790A	
P _D	Total Device Dissipation	2	W
$R_{\theta JA}$	Thermal Resistance, Junction to Ambient	62.5	°C/W

PNP Low Saturation Transistor

(continued)

Electrical Characteristics

T_{A = 25°C} unless otherwise noted

Symbol	Parameter	Test Conditions	Min	Max	Units
OFF CHAI	RACTERISTICS				
BV _{CEO}	Collector-Emitter Breakdown Voltage	I _C = 10 mA	40		V
BV _{CBO}	Collector-Base Breakdown Voltage	I _C = 100 μA	50		V
BV _{EBO}	Emitter-Base Breakdown Voltage	I _E = 100 μA	5		V
I _{CBO}	Collector Cutoff Current	V _{CB} = 30 V		100	nA
		$V_{CB} = 30 \text{ V}, T_A = 100^{\circ}\text{C}$		10	uA
I _{EBO}	Emitter Cutoff Current	V _{EB} = 4V		100	nA
ON CHAR	ACTERISTICS*		-1	•	
h _{FE}	DC Current Gain	I _C = 10 mA, V _{CE} = 2 V	300	800	-
		$I_C = 500 \text{ mA}, V_{CE} = 2 \text{ V}$	250		
		$I_C = 1 A, V_{CE} = 2 V$	200		
		$I_C = 2 A, V_{CE} = 2 V$	150		
VCE(sat)	Collector-Emitter Saturation Voltage	I _C = 500 mA, I _B = 5 mA		250	mV
		$I_C = 1 \text{ A}, I_B = 10 \text{ mA}$		450	
		$I_C = 2 \text{ A}, I_B = 50 \text{ mA}$		750	
V _{BE(sat)}	Base-Emitter Saturation Voltage	I _C = 1 A, I _B = 10 mA		1	V
SMALL SI	GNAL CHARACTERISTICS				
f _T	Transition Frequency	$I_C = 50 \text{ mA}, V_{CE} = 5 \text{ V}, f=50 \text{MHz}$	100		-
	ı				

*Pulse Test: Pulse Width ≤ 300 μs, Duty Cycle ≤ 2.0%